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Sommario/riassunto	Information technology (IT) has progressively grown in importance to space exploration efforts and today it often dominates the costs and schedules of space mission projects The International Conference on Space Mission Challenges for Information Technology (SMC IT) is the first forum to gather system and software engineers, scientists, and other practitioners with the objective of advancing information technology for space missions The forum provides an excellent opportunity for technical interchange for all aspects of IT used for space missions The conference will emphasize current and emerging IT practice and challenges for future space missions All aspects of the space mission will be explored, including flight systems, ground systems, science data processing, engineering and development tools, operations, and telecommunications The entire IT lifecycle of mission development will be considered.

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